

N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	200				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0. 91				
Q _g (Max.) (nC)	13				
Q _{gs} (nC)	3.0				
Q _{gd} (nC)	7.9				
Configuration	Single				

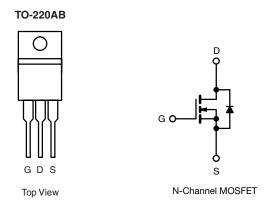
FEATURES

- TrenchFET® Power MOSFET
- 175 °C Junction Temperature
- **PWM Optimized**
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC



APPLICATIONS

· Primary Side Switch



ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V_{DS}	200	V		
Gate-Source Voltage			V_{GS}	± 20	v	
Continuous Drain Current	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	- I _D	5.0		
	VGS at 10 V	T _C = 100 °C		4.0	Α	
Pulsed Drain Current ^a			I _{DM}	20		
Linear Derating Factor				0.33	W/°C	
Linear Derating Factor (PCB Mount) e				0.020	VV/ C	
Single Pulse Avalanche Energy b			E _{AS}	161	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4.8	А	
Repetitive Avalanche Energy ^a			E _{AR}	4.2	mJ	
Maximum Power Dissipation	T _C =	T _C = 25 °C		42	W	
Maximum Power Dissipation (PCB mount) e	T _A = 25 °C		PD	P _D 2.5		
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	- °C	
Soldering Recommendations (Peak temperature) d	for	for 10 s		260	7	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=14~mH, $R_g=25~\Omega$, $I_{AS}=4.8~A$ (see fig. 12). c. $I_{SD}\leq5.2~A$, $I_{AS}=4.8~A$ (see fig. 12).

- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).

服务热线:400-655-8788

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	-	110	
Maximum Junction-to-Ambient (PCB mount) ^a	R _{thJA}	-	-	50	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	3.0	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					I.	l .	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.29	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	- V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V	-		± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 200 V, V _{GS} = 0 V	-	-	25	μA
During On One Order Brainlean			V, V _{GS} = 0 V, T _J = 125 °C	-	-	250	-
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.9 A b	-	0.91	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	: 50 V, I _D = 2.9 A ^b	1.7	-	-	S
Dynamic		T			I	ı	
Input Capacitance	C _{iss}	_	$V_{GS} = 0 V$	-	185	-	_
Output Capacitance	C _{oss}	f _ 1	$V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		100	-	pF
Reverse Transfer Capacitance	C _{rss}	T = 1.0 IVITIZ, See fig. 5		-	30	-	
Total Gate Charge	Qg	-	$I_D = 4.8 \text{ A}, V_{DS} = 160 \text{ V},$	-	-	13.0	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$	V _{GS} = 10 V see fig. 6 and 13 b		-	3.0	nC
Gate-Drain Charge	Q_{gd}				-	7.9	
Turn-On Delay Time	t _{d(on)}	V_{DD} = 100 V, I_{D} = 4.8 A, R_{G} = 18 Ω , R_{D} = 20 Ω , see fig. 10 b		-	7.2	-	
Rise Time	t _r			-	22	-	ns
Turn-Off Delay Time	$t_{d(off)}$			-	19	-	
Fall Time	t _f			-	13	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		1	4.5	-	nH
Internal Source Inductance	L _S			-	7.5	-	1111
Drain-Source Body Diode Characteristic	s				I.	l .	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.8	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	19	A
Body Diode Voltage	V_{SD}	T _J = 25 °C	T _J = 25 °C, I _S = 4.8 A, V _{GS} = 0 V ^b		-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 4.8 A, dl/dt = 100 A/µs b		-	150	300	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.91	1.8	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				[D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 $\mu s;$ duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

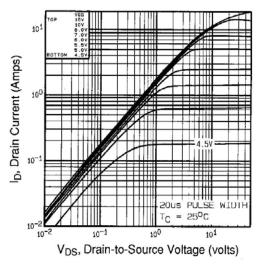


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

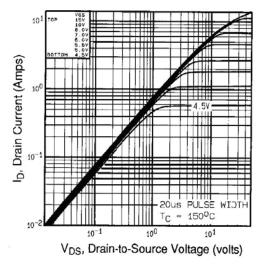


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

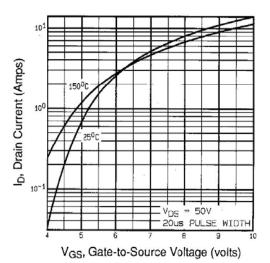


Fig. 3 - Typical Transfer Characteristics

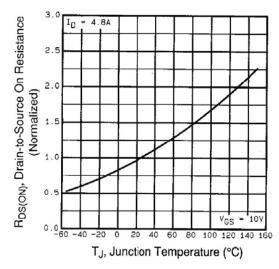


Fig. 4 - Normalized On-Resistance vs. Temperature



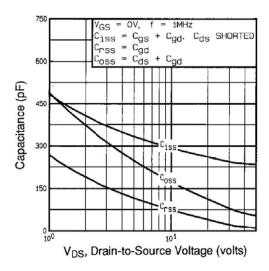


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

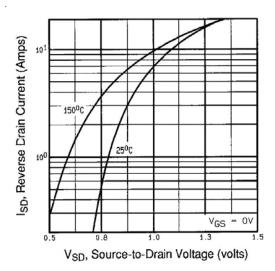


Fig. 7 - Typical Source-Drain Diode Forward Voltage

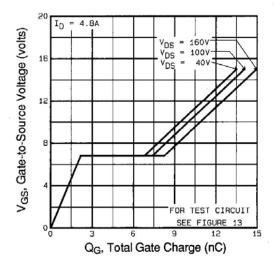


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

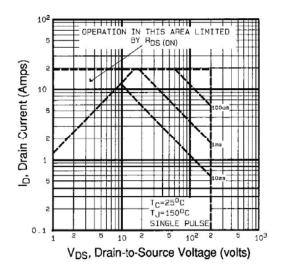


Fig. 8 - Maximum Safe Operating Area



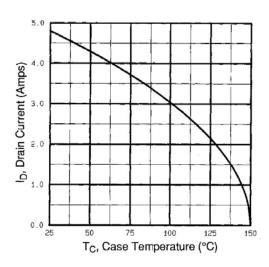


Fig. 9 - Maximum Drain Current vs. Case Temperature

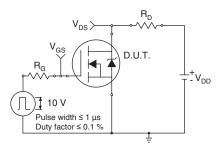


Fig. 10a - Switching Time Test Circuit

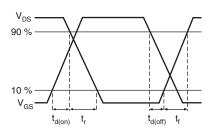


Fig. 10b - Switching Time Waveforms

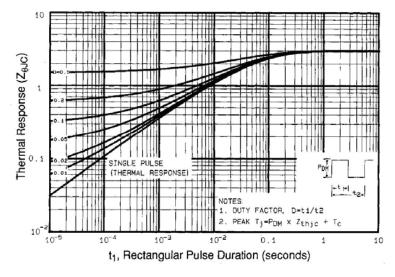


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



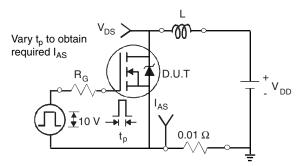


Fig. 12a - Unclamped Inductive Test Circuit

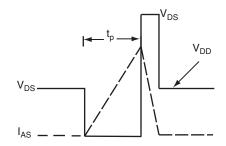


Fig. 12b - Unclamped Inductive Waveforms

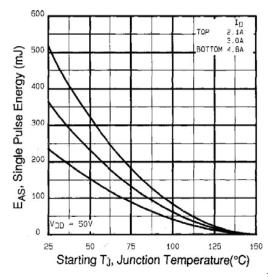


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

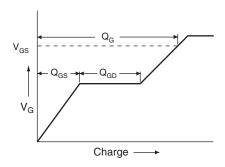


Fig. 13a - Basic Gate Charge Waveform

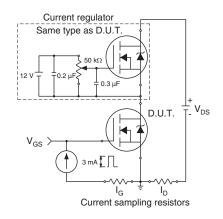
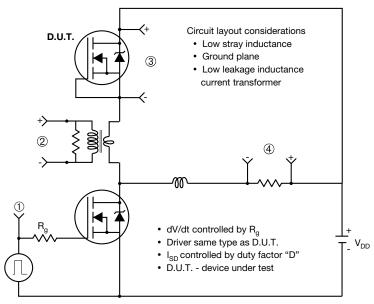


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



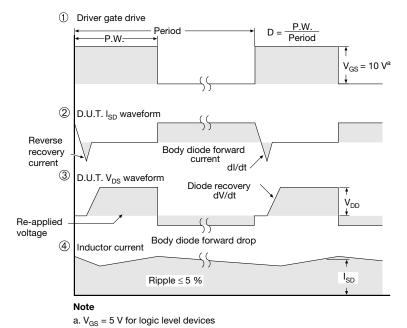
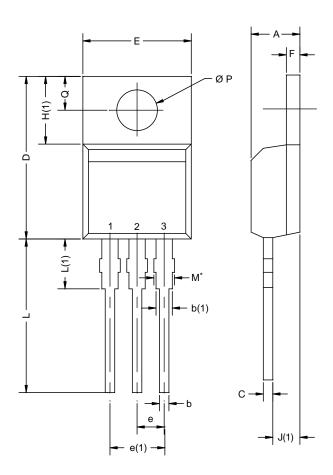


Fig. 14 - For N-Channel



TO-220AB



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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